

Notice of References Cited

Application/Control No.

10/615,702

Applicant(s)/Patent Under
Reexamination
MOCK, WAYNE E.

Examiner

GELEK TOPGYAL

Art Unit

2621

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,139,983	11-2006	Kelts, Brett R.	715/802
*	B	US-5,966,120	10-1999	Arazi et al.	715/724
*	C	US-2002/0026645 A1	02-2002	Son et al.	725/117
*	D	US-2002/0047899 A1	04-2002	Son et al.	348/114
*	E	US-2002/0078456 A1	06-2002	Hudson et al.	725/60
*	F	US-6,407,680 B1	06-2002	Lai et al.	341/50
*	G	US-2002/0088011 A1	07-2002	Lamkin et al.	725/142
*	H	US-2003/0098869 A1	05-2003	Arnold et al.	345/589
*	I	US-6,615,039 B1	09-2003	Eldering, Charles A.	455/418
*	J	US-2004/0210896 A1	10-2004	Chou et al.	717/174
*	K	US-6,898,800 B2	05-2005	Son et al.	725/93
*	L	US-7,020,704 B1	03-2006	Lipscomb et al.	709/226
*	M	US-7,106,799 B1	09-2006	Sostawa et al.	375/240.24

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.